

RELIABILITY TEST RESULT

Product name : S-93A66BD0A-A8TxU3

Package type : HSNT-8(2030)

No.	Test item	Test Condition	Test Time	r/n	Criterion
1	High-temperature operation	Ta=125 °C, V=Vopr max.	2000 h	0/22	Satisfies the product standard
2	Temperature humidity bias #1	Ta=85 °C, RH=85 %, V=Vopr max.	2000 h	0/22	Satisfies the product standard
3	Pressure cooker bias #1	Ta=130 °C, RH=85 %, P=2.3×10 ⁵ Pa V=Vopr max.	96 h	0/22	Satisfies the product standard
4	Storage in high temperature	Ta=150 °C	2000 h	0/22	Satisfies the product standard
5	Storage in low temperature	Ta=-65 °C	2000 h	0/22	Satisfies the product standard
6	Write/Erase Cycle-1	Ta=85 °C, V=Vopr max.	1×10 ⁶ cycles	0/22	Satisfies the product standard
7	Write/Erase Cycle-2	Ta=105 °C, V=Vopr max.	8×10 ⁵ cycles	0/22	Satisfies the product standard
8	Write/Erase Cycle-3	Ta=125 °C, V=Vopr max.	5×10 ⁵ cycles	0/22	Satisfies the product standard
9	Temperature Cycle (Gas phase) #1	Ta=150 °C ⇔ -65 °C 15 minutes for each	1000 cycles	0/22	Satisfies the product standard
10	Resistance to soldering heat (reflow soldering) #2	T=260 °C , 10 s	3 times	0/22	Satisfies the product standard No abnormality by appearances
11	Solderability #3	T=245 °C Solder material : Sn-3.0Ag-0.5Cu	5 s	0/11	Zero cross time should be less than 3 seconds. Solder should be applied at 95% or more of solderability judgment area.
12	Whisker - 1 (Temperature / Humidity Storage)	Ta=30 °C, RH=60%	4000 h	0/6	Whisker should be less than 40μm
13	Whisker - 2 (Temperature Cycling)	Ta=85 °C ⇔ -40 °C	1500 cycles	0/6	Whisker should be less than 45μm
14	Whisker - 3 (High Temperature / Humidity Storage)	Ta=55 °C, RH=85 %	4000 h	0/6	Whisker should be less than 40μm
15	Solder Joint Reliability (shear test) #3	Ta=125 °C ⇔ -40 °C Solder material : Sn-3.0Ag-0.5Cu	2000 cycles	0/22	After temperature cycle test, keep strength for shear stress more than the 50 % of initial mean value.
16	ESD - 1 (Human Body Model)	V=±2000 V, C=100 pF, R=1.5 kΩ Ground : V _{CC} / GND	5 pulses	0/5	Satisfies the product standard
17	ESD - 2 (Charged Device Model)	V=±500V charged, discharged	1 pulse	0/5	Satisfies the product standard
18	Latch up 1 (Pulsed current injection test)	±100 mA, V =Vopr max.	1 pulse	0/5	No latch up
19	Latch up 2 (Vsupply overvoltage test)	The overvoltage specified when V = Vopr max.	1 pulse	0/5	No latch up

Remark : Vopr max. =Maximum operation voltage

#1,2,3 : Each test designated # is performed after Pre-Treatment finished.

Pre-Treatment consists of High Temperature Storage , Temperature Humidity Storage and Soldering Heat. (See the table below.)

Pre Treatment (#1)		
High Temp. Storage	Temperature Humidity Storage	Soldering Heat
Ta=125 °C t=24 h	Ta=85 °C RH=85 % t=168 h	Reflow 3 times T=260 °C t=10 s

Pre Treatment (#2)		
High Temp. Storage	Temperature Humidity Storage	Soldering Heat
Ta=125 °C t=24 h	Ta=85 °C RH=85 % t=168 h	—

Pre Treatment (#3)		
High Temp. Storage	Temperature Humidity Storage	Soldering Heat
—	Ta=105 °C RH=100 % t=8 h	—